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### Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

### Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

#### Details

Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	50MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	3.3V
Operating Temperature	0°C ~ 95°C (TA)
Security Features	-
Package / Case	256-BGA
Supplier Device Package	256-PBGA (23x23)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/nxp-semiconductors/xpc850dezt50bu">https://www.e-xfl.com/product-detail/nxp-semiconductors/xpc850dezt50bu</a>

- Separate power supply input to operate internal logic at 2.2 V when operating at or below 25 MHz
- Can be dynamically shifted between high frequency (3.3 V internal) and low frequency (2.2 V internal) operation
- Debug interface
  - Eight comparators: four operate on instruction address, two operate on data address, and two operate on data
  - The MPC850 can compare using the =, ≠, <, and > conditions to generate watchpoints
  - Each watchpoint can generate a breakpoint internally
- 3.3-V operation with 5-V TTL compatibility on all general purpose I/O pins.

### 3 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC850. [Table 2](#) provides the maximum ratings.

**Table 2. Maximum Ratings**

(GND = 0V)

Rating	Symbol	Value	Unit
Supply voltage	VDDH	-0.3 to 4.0	V
	VDDL	-0.3 to 4.0	V
	KAPWR	-0.3 to 4.0	V
	VDDSYN	-0.3 to 4.0	V
Input voltage <sup>1</sup>	V <sub>in</sub>	GND-0.3 to VDDH + 2.5 V	V
Junction temperature <sup>2</sup>	T <sub>j</sub>	0 to 95 (standard) -40 to 95 (extended)	°C
Storage temperature range	T <sub>stg</sub>	-55 to +150	°C

<sup>1</sup> Functional operating conditions are provided with the DC electrical specifications in [Table 5](#). Absolute maximum ratings are stress ratings only; functional operation at the maxima is not guaranteed. Stress beyond those listed may affect device reliability or cause permanent damage to the device.

CAUTION: All inputs that tolerate 5 V cannot be more than 2.5 V greater than the supply voltage. This restriction applies to power-up and normal operation (that is, if the MPC850 is unpowered, voltage greater than 2.5 V must not be applied to its inputs).

<sup>2</sup> The MPC850, a high-frequency device in a BGA package, does not provide a guaranteed maximum ambient temperature. Only maximum junction temperature is guaranteed. It is the responsibility of the user to consider power dissipation and thermal management. Junction temperature ratings are the same regardless of frequency rating of the device.

This device contains circuitry protecting against damage due to high-static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for example, either GND or V<sub>CC</sub>). [Table 3](#) provides the package thermal characteristics for the MPC850.

## 4 Thermal Characteristics

Table 3 shows the thermal characteristics for the MPC850.

**Table 3. Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Thermal resistance for BGA <sup>1</sup>	$\theta_{JA}$	40 <sup>2</sup>	°C/W
	$\theta_{JA}$	31 <sup>3</sup>	°C/W
	$\theta_{JA}$	24 <sup>4</sup>	°C/W
Thermal Resistance for BGA (junction-to-case)	$\theta_{JC}$	8	°C/W

<sup>1</sup> For more information on the design of thermal vias on multilayer boards and BGA layout considerations in general, refer to AN-1231/D, Plastic Ball Grid Array Application Note available from your local Freescale sales office.

<sup>2</sup> Assumes natural convection and a single layer board (no thermal vias).

<sup>3</sup> Assumes natural convection, a multilayer board with thermal vias<sup>4</sup>, 1 watt MPC850 dissipation, and a board temperature rise of 20°C above ambient.

<sup>4</sup> Assumes natural convection, a multilayer board with thermal vias<sup>4</sup>, 1 watt MPC850 dissipation, and a board temperature rise of 13°C above ambient.

$$T_J = T_A + (P_D \bullet \theta_{JA})$$

$$P_D = (V_{DD} \bullet I_{DD}) + P_{I/O}$$

where:

$P_{I/O}$  is the power dissipation on pins

Table 4 provides power dissipation information.

**Table 4. Power Dissipation ( $P_D$ )**

Characteristic	Frequency (MHz)	Typical <sup>1</sup>	Maximum <sup>2</sup>	Unit
Power Dissipation All Revisions (1:1) Mode	33	TBD	515	mW
	40	TBD	590	mW
	50	TBD	725	mW

<sup>1</sup> Typical power dissipation is measured at 3.3V

<sup>2</sup> Maximum power dissipation is measured at 3.65 V

Table 5 provides the DC electrical characteristics for the MPC850.

**Table 5. DC Electrical Specifications**

Characteristic	Symbol	Min	Max	Unit
Operating voltage at 40 MHz or less	VDDH, VDDL, KAPWR, VDDSYN	3.0	3.6	V
Operating voltage at 40 MHz or higher	VDDH, VDDL, KAPWR, VDDSYN	3.135	3.465	V
Input high voltage (address bus, data bus, EXTAL, EXTCLK, and all bus control/status signals)	VIH	2.0	3.6	V
Input high voltage (all general purpose I/O and peripheral pins)	VIH	2.0	5.5	V

Table 5. DC Electrical Specifications (continued)

Characteristic	Symbol	Min	Max	Unit
Input low voltage	VIL	GND	0.8	V
EXTAL, EXTCLK input high voltage	VIHC	0.7*(VCC)	VCC+0.3	V
Input leakage current, Vin = 5.5 V (Except TMS, $\overline{\text{TRST}}$ , DSCK and DSDI pins)	I <sub>in</sub>	—	100	μA
Input leakage current, Vin = 3.6V (Except TMS, $\overline{\text{TRST}}$ , DSCK and DSDI pins)	I <sub>in</sub>	—	10	μA
Input leakage current, Vin = 0V (Except TMS, $\overline{\text{TRST}}$ , DSCK and DSDI pins)	I <sub>in</sub>	—	10	μA
Input capacitance	C <sub>in</sub>	—	20	pF
Output high voltage, IOH = -2.0 mA, VDDH = 3.0V except XTAL, XFC, and open-drain pins	VOH	2.4	—	V
Output low voltage CLKOUT <sup>3</sup> IOL = 3.2 mA <sup>1</sup> IOL = 5.3 mA <sup>2</sup> IOL = 7.0 mA PA[14]/ $\overline{\text{USBOE}}$ , PA[12]/TXD2 IOL = 8.9 mA $\overline{\text{TS}}$ , $\overline{\text{TA}}$ , $\overline{\text{TEA}}$ , $\overline{\text{BI}}$ , $\overline{\text{BB}}$ , $\overline{\text{HRESET}}$ , $\overline{\text{SRESET}}$	VOL	—	0.5	V

<sup>1</sup> A[6:31], TSIZ0/ $\overline{\text{REG}}$ , TSIZ1, D[0:31], DP[0:3]/ $\overline{\text{IRQ}}[3:6]$ , RD/ $\overline{\text{WR}}$ , BURST, RSV/ $\overline{\text{IRQ2}}$ , IP\_B[0:1]/IWP[0:1]/VFLS[0:1], IP\_B2/ $\overline{\text{IOIS16\_B/AT2}}$ , IP\_B3/IWP2/VF2, IP\_B4/LWP0/VF0, IP\_B5/LWP1/VF1, IP\_B6/DSDI/AT0, IP\_B7/ $\overline{\text{PTR/AT3}}$ , PA[15]/ $\overline{\text{USBRXD}}$ , PA[13]/RXD2, PA[9]/L1TXDA/SMRXD2, PA[8]/L1RXDA/SMTXD2, PA[7]/CLK1/TIN1/L1RCLKA/BRGO1, PA[6]/CLK2/TOUT1/TIN3, PA[5]/CLK3/TIN2/L1TCLKA/BRGO2, PA[4]/CLK4/TOUT2/TIN4, PB[31]/SPISEL, PB[30]/SPICLK/TXD3, PB[29]/SPIMOSI /RXD3, PB[28]/SPIMISO/BRGO3, PB[27]/I2CSDA/BRGO1, PB[26]/I2CSCL/BRGO2, PB[25]/SMTXD1/TXD3, PB[24]/SMRXD1/RXD3, PB[23]/SMSYN1/SDACK1, PB[22]/SMSYN2/SDACK2, PB[19]/L1ST1, PB[18]/RTS2/L1ST2, PB[17]/L1ST3, PB[16]/L1RQa/L1ST4, PC[15]/DREQ0/L1ST5, PC[14]/DREQ1/RTS2/L1ST6, PC[13]/L1ST7/RTS3, PC[12]/L1RQa/L1ST8, PC[11]/ $\overline{\text{USBRXP}}$ , PC[10]/TGATE1/ $\overline{\text{USBRXN}}$ , PC[9]/CTS2, PC[8]/CD2/TGATE1, PC[7]/ $\overline{\text{USBTXP}}$ , PC[6]/ $\overline{\text{USBTXN}}$ , PC[5]/CTS3/L1TSYNCA/SDACK1, PC[4]/CD3/L1RSYNCA, PD[15], PD[14], PD[13], PD[12], PD[11], PD[10], PD[9], PD[8], PD[7], PD[6], PD[5], PD[4], PD[3]

<sup>2</sup>  $\overline{\text{BDIP/GPL\_B5}}$ ,  $\overline{\text{BR}}$ ,  $\overline{\text{BG}}$ , FRZ/ $\overline{\text{IRQ6}}$ ,  $\overline{\text{CS}}[0:5]$ ,  $\overline{\text{CS6/CE1\_B}}$ ,  $\overline{\text{CS7/CE2\_B}}$ ,  $\overline{\text{WE0/BS\_AB0/IORD}}$ ,  $\overline{\text{WE1/BS\_AB1/IOWR}}$ ,  $\overline{\text{WE2/BS\_AB2/PCOE}}$ ,  $\overline{\text{WE3/BS\_AB3/PCWE}}$ ,  $\overline{\text{GPL\_A0/GPL\_B0}}$ ,  $\overline{\text{OE/GPL\_A1/GPL\_B1}}$ ,  $\overline{\text{GPL\_A2:3/GPL\_B2:3/CS2:3}}$ , UPWAITA/ $\overline{\text{GPL\_A4/AS}}$ , UPWAITB/ $\overline{\text{GPL\_B4}}$ ,  $\overline{\text{GPL\_A5}}$ ,  $\overline{\text{ALE\_B/DSCK/AT1}}$ , OP2/MODCK1/STS, OP3/MODCK2/SDO

<sup>3</sup> The MPC850 IBIS model must be used to accurately model the behavior of the Clkout output driver for the full and half drive setting. Due to the nature of the Clkout output buffer, IOH and IOL for Clkout should be extracted from the IBIS model at any output voltage level.

## 5 Power Considerations

The average chip-junction temperature, T<sub>J</sub>, in °C can be obtained from the equation:

$$T_J = T_A + (P_D \cdot \theta_{JA})(1)$$

where

$$T_A = \text{Ambient temperature, } ^\circ\text{C}$$

Table 6. Bus Operation Timing <sup>1</sup> (continued)

Num	Characteristic	50 MHz		66 MHz		80 MHz		FFACT	Cap Load (default 50 pF)	Unit
		Min	Max	Min	Max	Min	Max			
B22	CLKOUT rising edge to $\overline{CS}$ asserted GPCM ACS = 00	5.00	11.75	7.58	14.33	6.25	13.00	0.250	50.00	ns
B22a	CLKOUT falling edge to $\overline{CS}$ asserted GPCM ACS = 10, TRLX = 0,1	—	8.00	—	8.00	—	8.00	—	50.00	ns
B22b	CLKOUT falling edge to $\overline{CS}$ asserted GPCM ACS = 11, TRLX = 0, EBDF = 0	5.00	11.75	7.58	14.33	6.25	13.00	0.250	50.00	ns
B22c	CLKOUT falling edge to $\overline{CS}$ asserted GPCM ACS = 11, TRLX = 0, EBDF = 1	7.00	14.00	11.00	18.00	9.00	16.00	0.375	50.00	ns
B23	CLKOUT rising edge to $\overline{CS}$ negated GPCM read access, GPCM write access ACS = 00, TRLX = 0 & CSNT = 0	2.00	8.00	2.00	8.00	2.00	8.00	—	50.00	ns
B24	A[6–31] to $\overline{CS}$ asserted GPCM ACS = 10, TRLX = 0.	3.00	—	6.00	—	4.00	—	0.250	50.00	ns
B24a	A[6–31] to $\overline{CS}$ asserted GPCM ACS = 11, TRLX = 0	8.00	—	13.00	—	11.00	—	0.500	50.00	ns
B25	CLKOUT rising edge to $\overline{OE}$ , WE[0–3] asserted	—	9.00	—	9.00	—	9.00	—	50.00	ns
B26	CLKOUT rising edge to $\overline{OE}$ negated	2.00	9.00	2.00	9.00	2.00	9.00	—	50.00	ns
B27	A[6–31] to $\overline{CS}$ asserted GPCM ACS = 10, TRLX = 1	23.00	—	36.00	—	29.00	—	1.250	50.00	ns
B27a	A[6–31] to $\overline{CS}$ asserted GPCM ACS = 11, TRLX = 1	28.00	—	43.00	—	36.00	—	1.500	50.00	ns
B28	CLKOUT rising edge to WE[0–3] negated GPCM write access CSNT = 0	—	9.00	—	9.00	—	9.00	—	50.00	ns
B28a	CLKOUT falling edge to WE[0–3] negated GPCM write access TRLX = 0,1 CSNT = 1, EBDF = 0	5.00	12.00	8.00	14.00	6.00	13.00	0.250	50.00	ns
B28b	CLKOUT falling edge to $\overline{CS}$ negated GPCM write access TRLX = 0,1 CSNT = 1, ACS = 10 or ACS = 11, EBDF = 0	—	12.00	—	14.00	—	13.00	0.250	50.00	ns

Table 6. Bus Operation Timing <sup>1</sup> (continued)

Num	Characteristic	50 MHz		66 MHz		80 MHz		FFACTOR	Cap Load (default 50 pF)	Unit
		Min	Max	Min	Max	Min	Max			
B42	CLKOUT rising edge to $\overline{TS}$ valid (hold time)	2.00	—	2.00	—	2.00	—	—	50.00	ns
B43	$\overline{AS}$ negation to memory controller signals negation	—	TBD	—	TBD	TBD	—	—	50.00	ns

<sup>1</sup> The minima provided assume a 0 pF load, whereas maxima assume a 50pF load. For frequencies not marked on the part, new bus timing must be calculated for all frequency-dependent AC parameters. Frequency-dependent AC parameters are those with an entry in the FFactor column. AC parameters without an FFactor entry do not need to be calculated and can be taken directly from the frequency column corresponding to the frequency marked on the part. The following equations should be used in these calculations.

For a frequency F, the following equations should be applied to each one of the above parameters:

For minima:

$$D = \frac{\text{FFACTOR} \times 1000}{F} + (D_{50} - 20 \times \text{FFACTOR})$$

For maxima:

$$D = \frac{\text{FFACTOR} \times 1000}{F} + (D_{50} - 20 \times \text{FFACTOR}) + 1\text{ns}(\text{CAP LOAD} - 50) / 10$$

where:

D is the parameter value to the frequency required in ns

F is the operation frequency in MHz

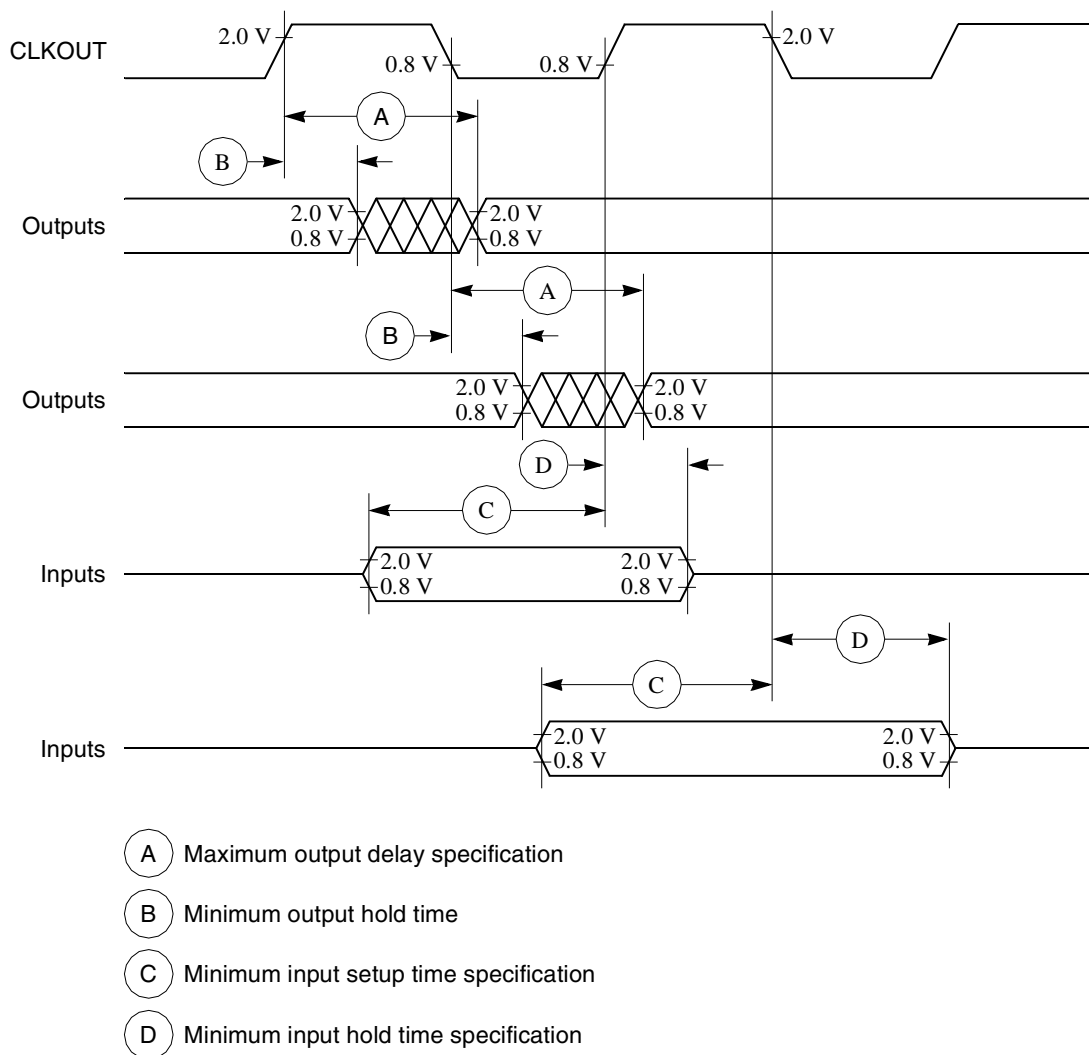
D<sub>50</sub> is the parameter value defined for 50 MHz

CAP LOAD is the capacitance load on the signal in question.

FFACTOR is the one defined for each of the parameters in the table.

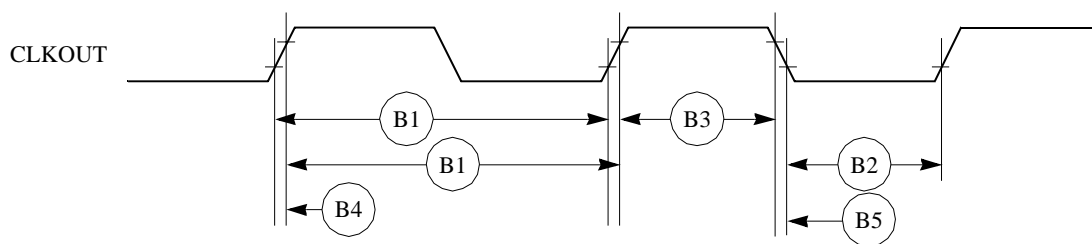
- <sup>2</sup> Phase and frequency jitter performance results are valid only if the input jitter is less than the prescribed value.
- <sup>3</sup> If the rate of change of the frequency of EXTAL is slow (i.e. it does not jump between the minimum and maximum values in one cycle) or the frequency of the jitter is fast (i.e., it does not stay at an extreme value for a long time) then the maximum allowed jitter on EXTAL can be up to 2%.
- <sup>4</sup> The timing for  $\overline{BR}$  output is relevant when the MPC850 is selected to work with external bus arbiter. The timing for  $\overline{BG}$  output is relevant when the MPC850 is selected to work with internal bus arbiter.
- <sup>5</sup> The setup times required for  $\overline{TA}$ ,  $\overline{TEA}$ , and  $\overline{BI}$  are relevant only when they are supplied by an external device (and not when the memory controller or the PCMCIA interface drives them).
- <sup>6</sup> The timing required for  $\overline{BR}$  input is relevant when the MPC850 is selected to work with the internal bus arbiter. The timing for  $\overline{BG}$  input is relevant when the MPC850 is selected to work with the external bus arbiter.
- <sup>7</sup> The D[0–31] and DP[0–3] input timings B20 and B21 refer to the rising edge of the CLKOUT in which the  $\overline{TA}$  input signal is asserted.
- <sup>8</sup> The D[0:31] and DP[0:3] input timings B20 and B21 refer to the falling edge of CLKOUT. This timing is valid only for read accesses controlled by chip-selects controlled by the UPM in the memory controller, for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.
- <sup>9</sup> The timing B30 refers to  $\overline{CS}$  when ACS = '00' and to  $\overline{WE}[0:3]$  when CSNT = '0'.
- <sup>10</sup> The signal UPWAIT is considered asynchronous to CLKOUT and synchronized internally. The timings specified in B37 and B38 are specified to enable the freeze of the UPM output signals.
- <sup>11</sup> The  $\overline{AS}$  signal is considered asynchronous to CLKOUT.

Figure 2 is the control timing diagram.



**Figure 2. Control Timing**

Figure 3 provides the timing for the external clock.



**Figure 3. External Clock Timing**

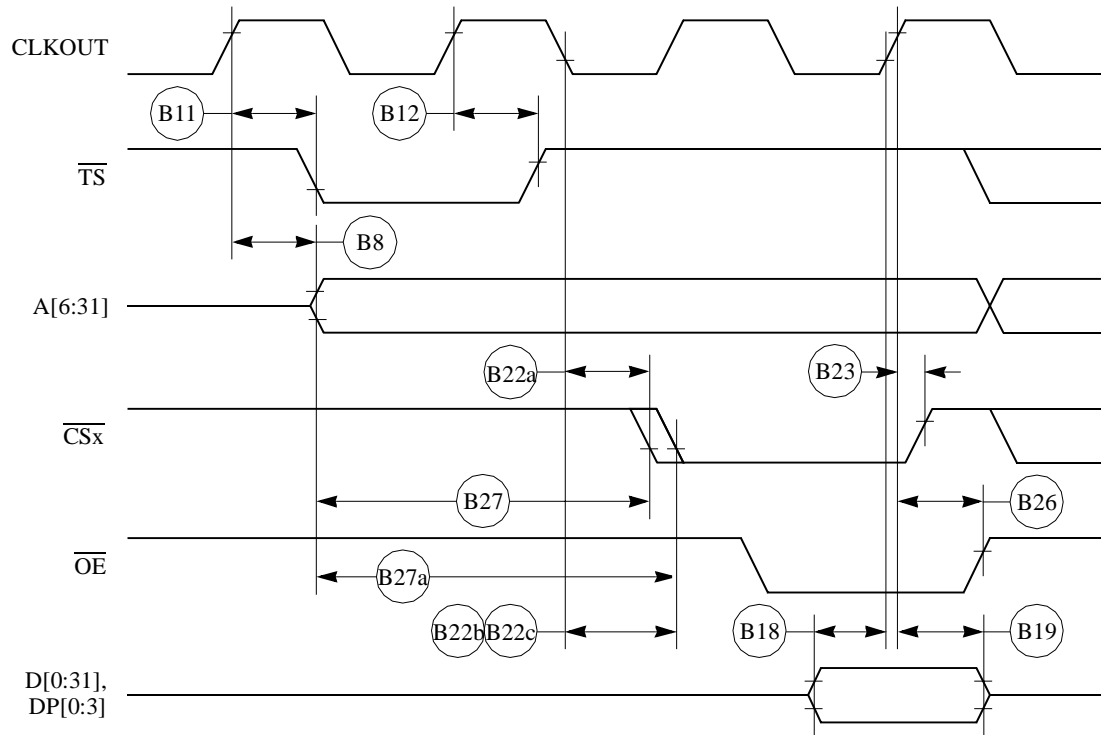


Figure 12. External Bus Read Timing (GPCM Controlled—TRLX = 1, ACS = 10, ACS = 11)



Figure 16 provides the timing for the external bus controlled by the UPM.

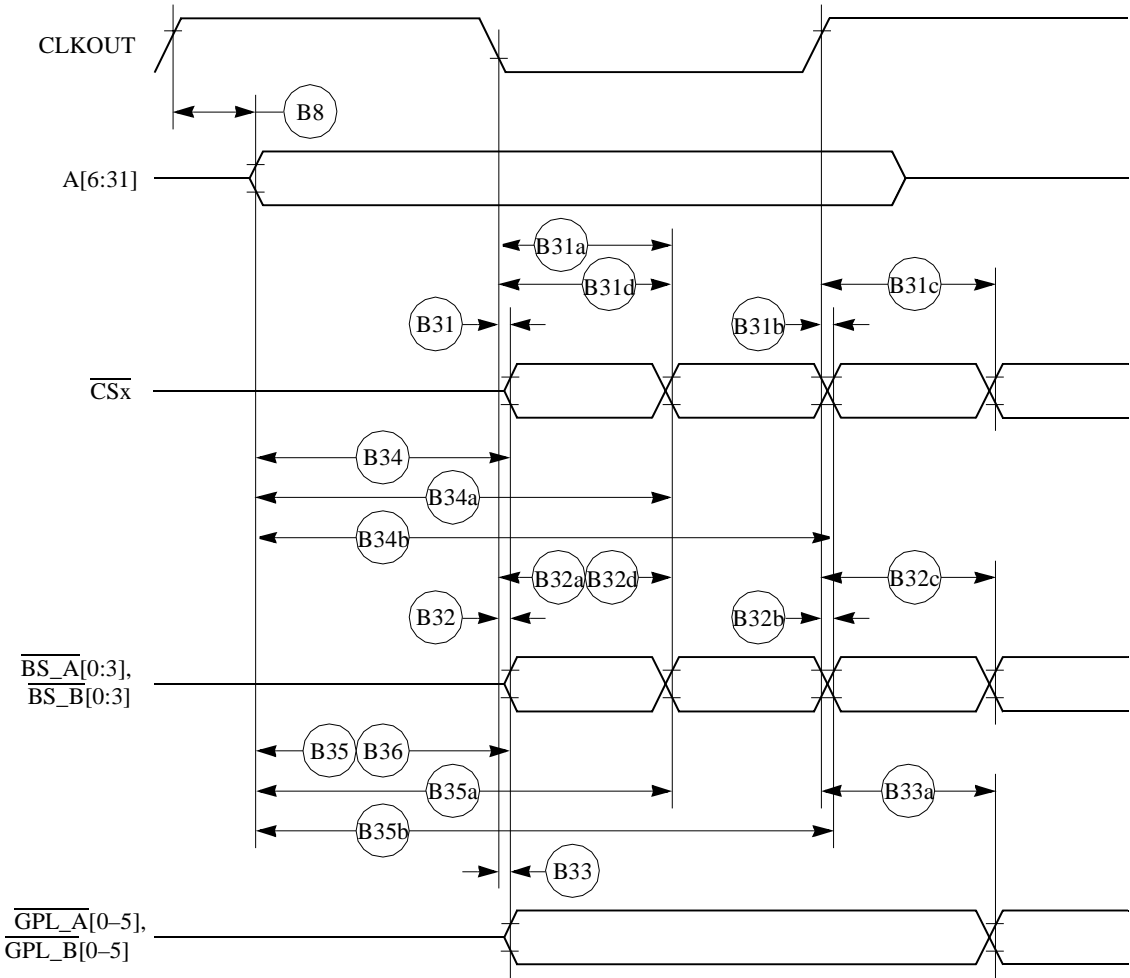


Figure 16. External Bus Timing (UPM Controlled Signals)

Table 7 provides interrupt timing for the MPC850.

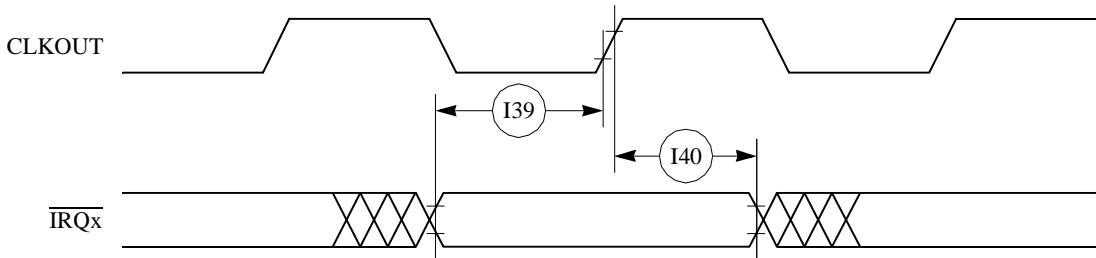
**Table 7. Interrupt Timing**

Num	Characteristic <sup>1</sup>	50 MHz		66MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	
I39	$\overline{\text{IRQx}}$ valid to CLKOUT rising edge (set up time)	6.00	—	6.00	—	6.00	—	ns
I40	$\overline{\text{IRQx}}$ hold time after CLKOUT.	2.00	—	2.00	—	2.00	—	ns
I41	$\overline{\text{IRQx}}$ pulse width low	3.00	—	3.00	—	3.00	—	ns
I42	$\overline{\text{IRQx}}$ pulse width high	3.00	—	3.00	—	3.00	—	ns
I43	$\overline{\text{IRQx}}$ edge-to-edge time	80.00	—	121.0	—	100.0	—	ns

<sup>1</sup> The timings I39 and I40 describe the testing conditions under which the  $\overline{\text{IRQ}}$  lines are tested when being defined as level sensitive. The  $\overline{\text{IRQ}}$  lines are synchronized internally and do not have to be asserted or negated with reference to the CLKOUT.

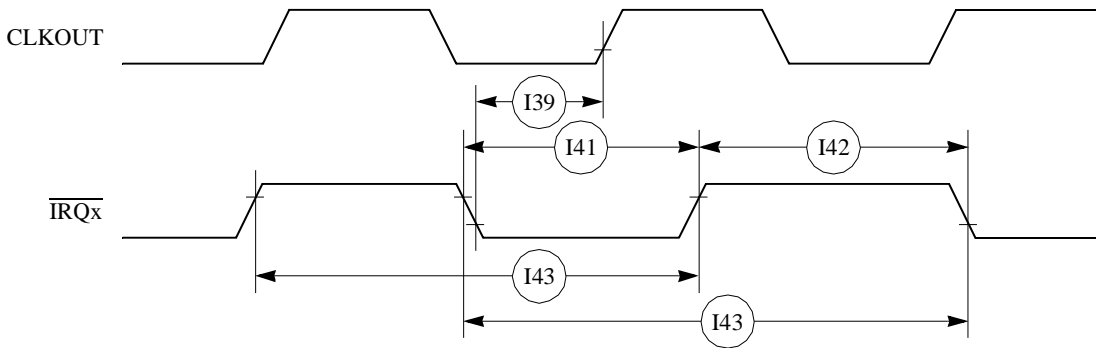
The timings I41, I42, and I43 are specified to allow the correct function of the  $\overline{\text{IRQ}}$  lines detection circuitry, and has no direct relation with the total system interrupt latency that the MPC850 is able to support

Figure 22 provides the interrupt detection timing for the external level-sensitive lines.



**Figure 22. Interrupt Detection Timing for External Level Sensitive Lines**

Figure 23 provides the interrupt detection timing for the external edge-sensitive lines.



**Figure 23. Interrupt Detection Timing for External Edge Sensitive Lines**

Figure 24 provides the PCMCIA access cycle timing for the external bus read.

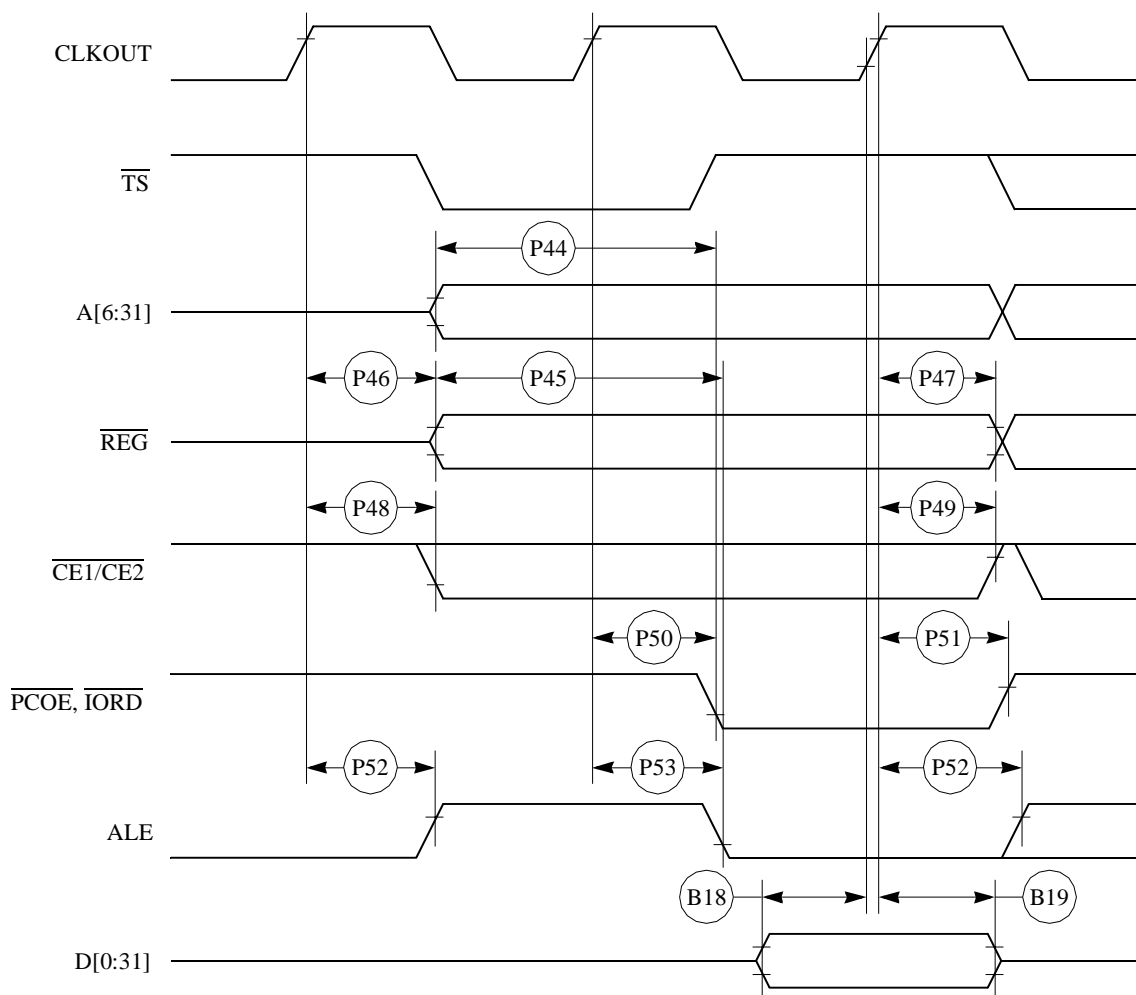


Figure 24. PCMCIA Access Cycles Timing External Bus Read

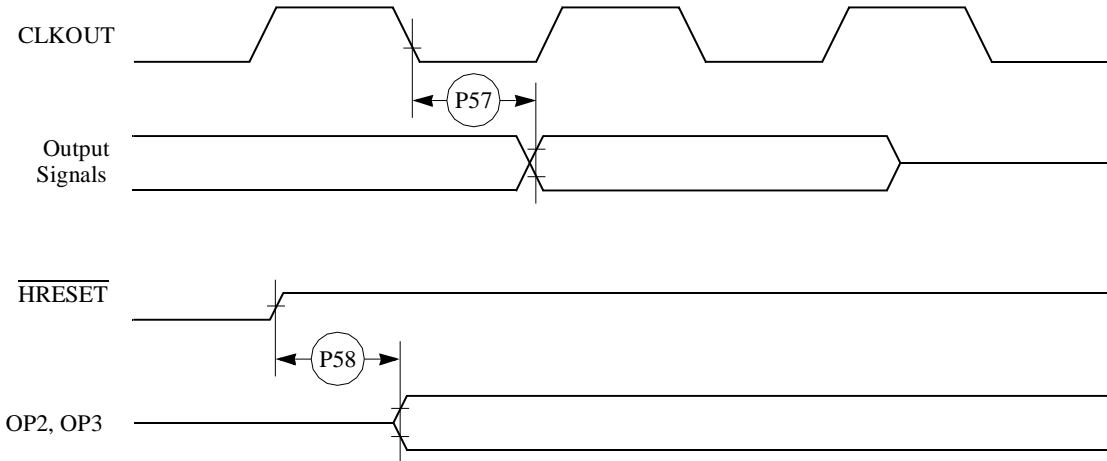
Table 9 shows the PCMCIA port timing for the MPC850.

**Table 9. PCMCIA Port Timing**

Num	Characteristic	50 MHz		66 MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	
P57	CLKOUT to OPx valid	—	19.00	—	19.00	—	19.00	ns
P58	$\overline{\text{HRESET}}$ negated to OPx drive <sup>1</sup>	18.00	—	26.00	—	22.00	—	ns
P59	IP_Xx valid to CLKOUT rising edge	5.00	—	5.00	—	5.00	—	ns
P60	CLKOUT rising edge to IP_Xx invalid	1.00	—	1.00	—	1.00	—	ns

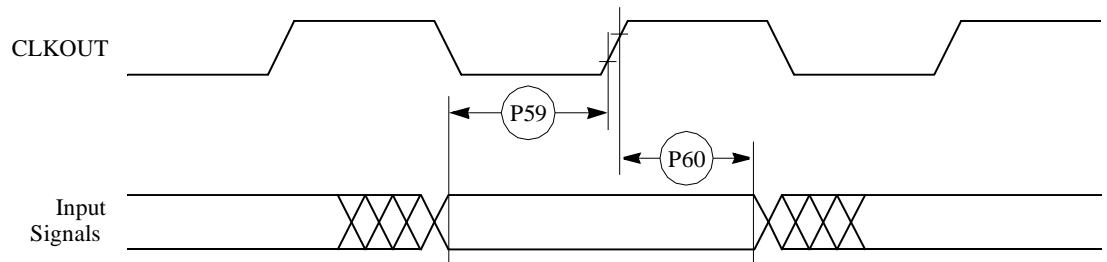
<sup>1</sup> OP2 and OP3 only.

Figure 27 provides the PCMCIA output port timing for the MPC850.



**Figure 27. PCMCIA Output Port Timing**

Figure 28 provides the PCMCIA output port timing for the MPC850.



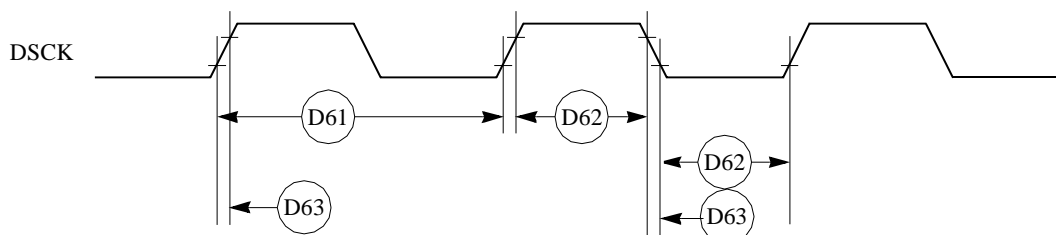
**Figure 28. PCMCIA Input Port Timing**

Table 10 shows the debug port timing for the MPC850.

**Table 10. Debug Port Timing**

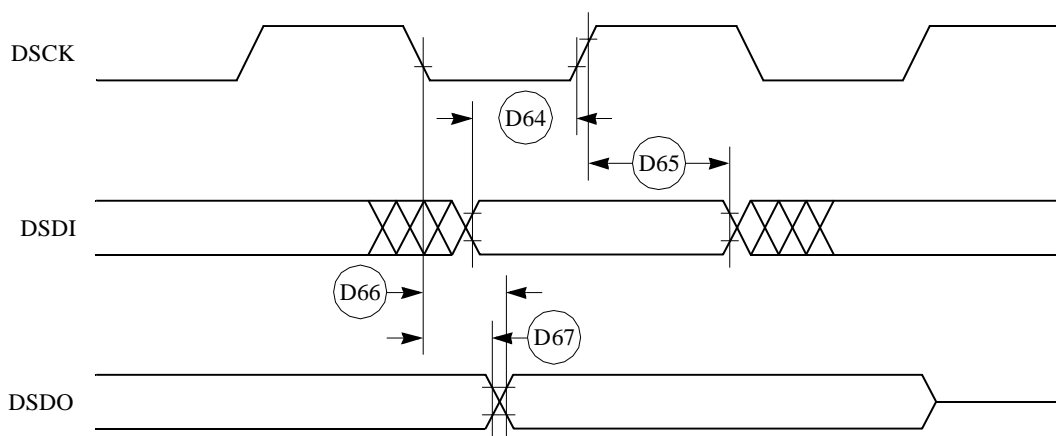
Num	Characteristic	50 MHz		66 MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	
D61	DSCK cycle time	60.00	—	91.00	—	75.00	—	ns
D62	DSCK clock pulse width	25.00	—	38.00	—	31.00	—	ns
D63	DSCK rise and fall times	0.00	3.00	0.00	3.00	0.00	3.00	ns
D64	DSDI input data setup time	8.00	—	8.00	—	8.00	—	ns
D65	DSDI data hold time	5.00	—	5.00	—	5.00	—	ns
D66	DSCK low to DSDO data valid	0.00	15.00	0.00	15.00	0.00	15.00	ns
D67	DSCK low to DSDO invalid	0.00	2.00	0.00	2.00	0.00	2.00	ns

Figure 29 provides the input timing for the debug port clock.



**Figure 29. Debug Port Clock Input Timing**

Figure 30 provides the timing for the debug port.



**Figure 30. Debug Port Timings**

## 8.3 Baud Rate Generator AC Electrical Specifications

Table 15 provides the baud rate generator timings as shown in Figure 43.

Table 15. Baud Rate Generator Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
50	BRGO rise and fall time	—	10.00	ns
51	BRGO duty cycle	40.00	60.00	%
52	BRGO cycle	40.00	—	ns

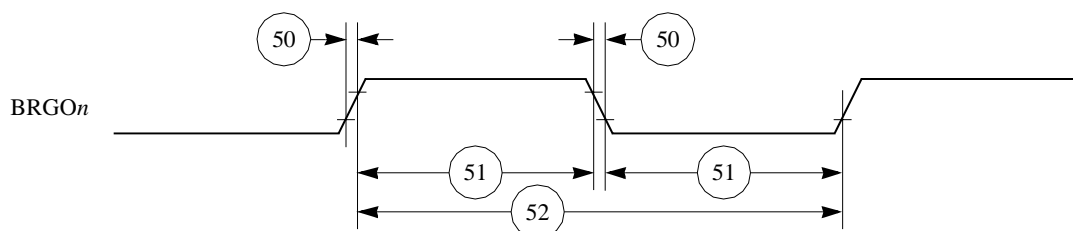


Figure 43. Baud Rate Generator Timing Diagram

## 8.4 Timer AC Electrical Specifications

Table 16 provides the baud rate generator timings as shown in Figure 44.

Table 16. Timer Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
61	TIN/TGATE rise and fall time	10.00	—	ns
62	TIN/TGATE low time	1.00	—	clk
63	TIN/TGATE high time	2.00	—	clk
64	TIN/TGATE cycle time	3.00	—	clk
65	CLKO high to TOUT valid	3.00	25.00	ns

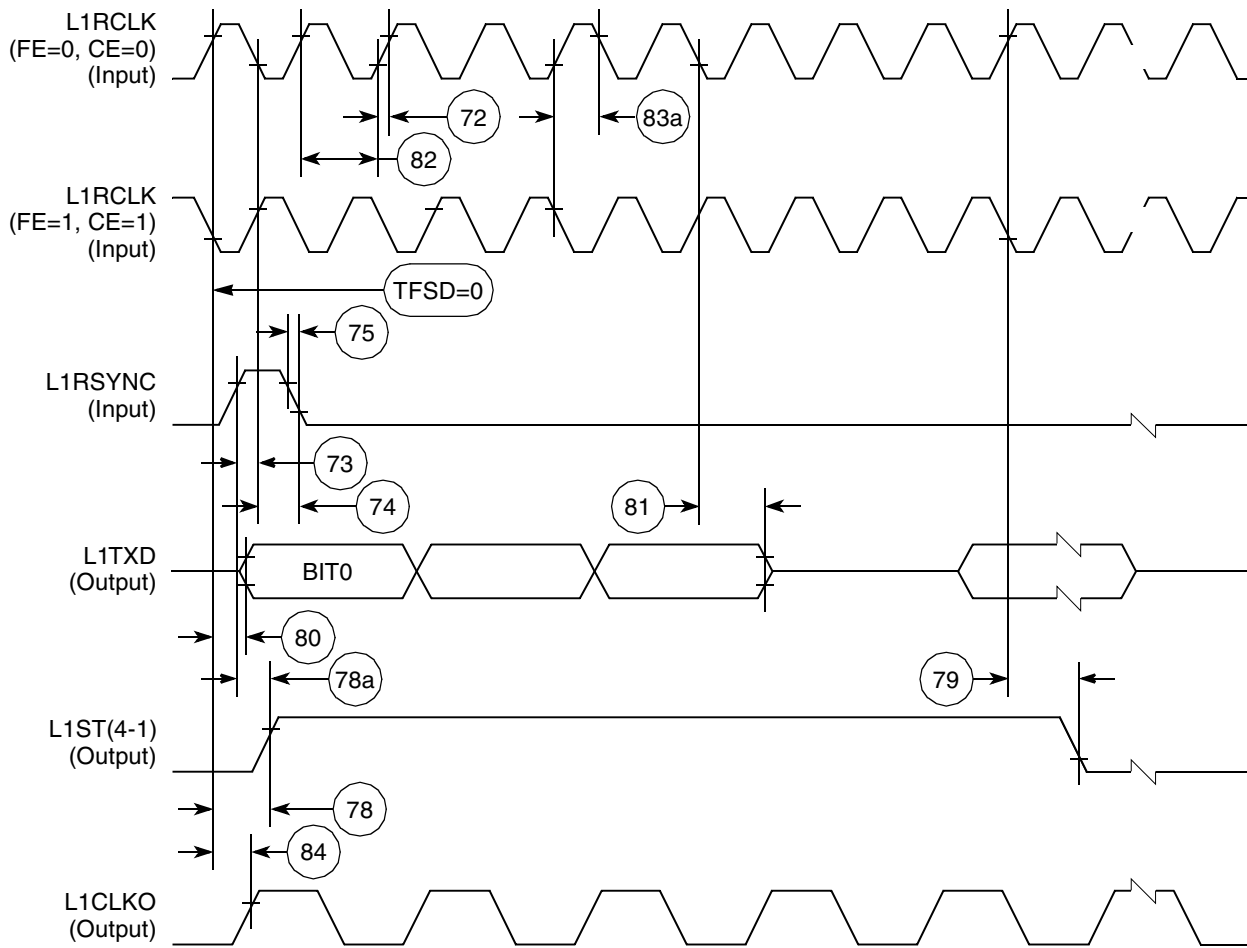


Figure 48. SI Transmit Timing with Double Speed Clocking (DSC = 1)

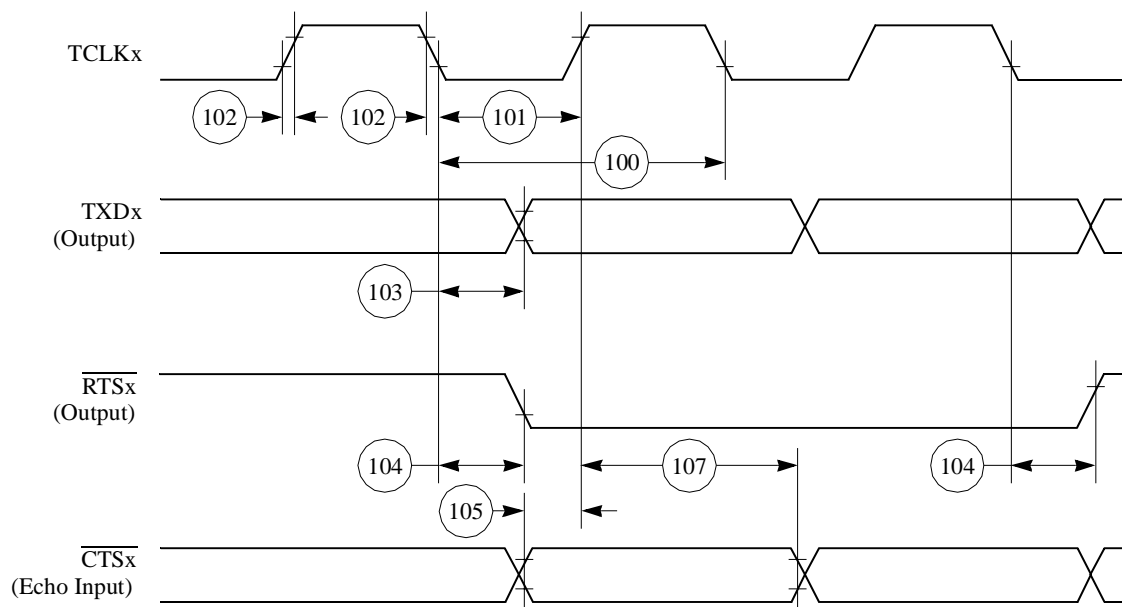


Figure 52. HDLC Bus Timing Diagram

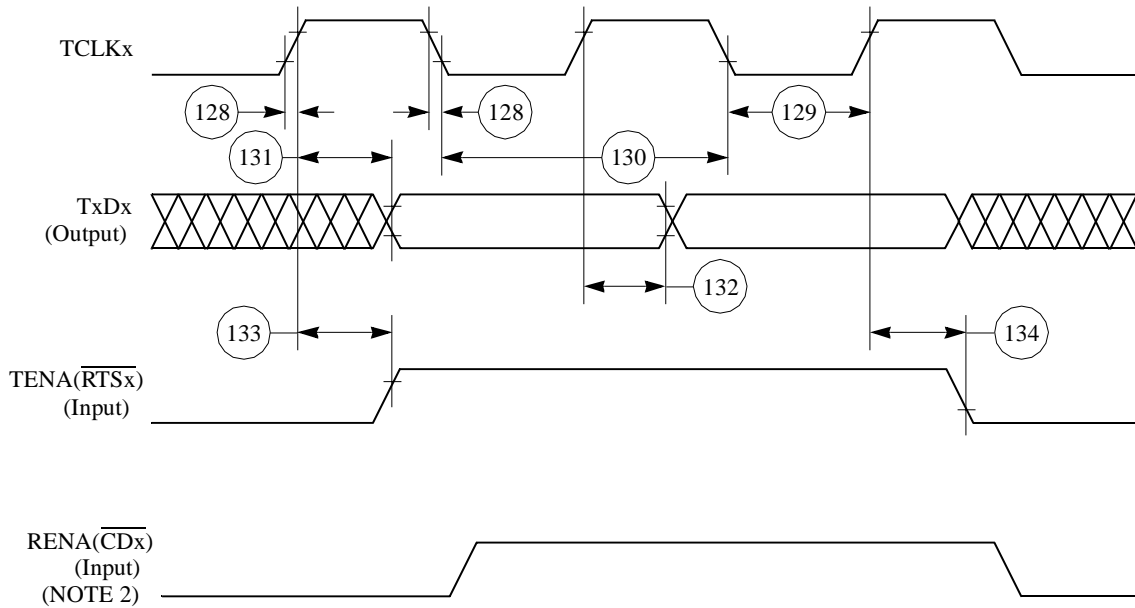
## 8.7 Ethernet Electrical Specifications

Table 20 provides the Ethernet timings as shown in Figure 53 to Figure 55.

Table 20. Ethernet Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
120	CLSN width high	40.00	—	ns
121	RCLKx rise/fall time (x = 2, 3 for all specs in this table)	—	15.00	ns
122	RCLKx width low	40.00	—	ns
123	RCLKx clock period <sup>1</sup>	80.00	120.00	ns
124	RXDx setup time	20.00	—	ns
125	RXDx hold time	5.00	—	ns
126	RENA active delay (from RCLKx rising edge of the last data bit)	10.00	—	ns
127	RENA width low	100.00	—	ns
128	TCLKx rise/fall time	—	15.00	ns
129	TCLKx width low	40.00	—	ns
130	TCLKx clock period <sup>1</sup>	99.00	101.00	ns
131	TXDx active delay (from TCLKx rising edge)	10.00	50.00	ns
132	TXDx inactive delay (from TCLKx rising edge)	10.00	50.00	ns
133	TENA active delay (from TCLKx rising edge)	10.00	50.00	ns





- NOTES:
1. Transmit clock invert (TCI) bit in GSMR is set.
  2. If RENA is deasserted before TENA, or RENA is not asserted at all during transmit, then the CSL bit is set in the buffer descriptor at the end of the frame transmission.

Figure 55. Ethernet Transmit Timing Diagram

## 8.8 SMC Transparent AC Electrical Specifications

Figure 21 provides the SMC transparent timings as shown in Figure 56.

Table 21. Serial Management Controller Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
150	SMCLKx clock period <sup>1</sup>	100.00	—	ns
151	SMCLKx width low	50.00	—	ns
151a	SMCLKx width high	50.00	—	ns
152	SMCLKx rise/fall time	—	15.00	ns
153	SMTXDx active delay (from SMCLKx falling edge)	10.00	50.00	ns
154	SMRXDx/SMSYNx setup time	20.00	—	ns
155	SMRXDx/SMSYNx hold time	5.00	—	ns

<sup>1</sup> The ratio SyncCLK/SMCLKx must be greater or equal to 2/1.

**Table 24. I<sup>2</sup>C Timing (SCL < 100 KHz) (CONTINUED)**

Num	Characteristic	All Frequencies		Unit
		Min	Max	
210	SDL/SCL fall time	—	300.00	ns
211	Stop condition setup time	4.70	—	μs

<sup>1</sup> SCL frequency is given by  $SCL = BRGCLK\_frequency / ((BRG\ register + 3) * pre\_scaler * 2)$ .  
The ratio SyncClk/(BRGCLK/pre\_scaler) must be greater or equal to 4/1.

Table 25 provides the I<sup>2</sup>C (SCL > 100 KHz) timings.

**Table 25. I<sup>2</sup>C Timing (SCL > 100 KHz)**

Num	Characteristic	Expression	All Frequencies		Unit
			Min	Max	
200	SCL clock frequency (slave)	fSCL	0	BRGCLK/48	Hz
200	SCL clock frequency (master) <sup>1</sup>	fSCL	BRGCLK/16512	BRGCLK/48	Hz
202	Bus free time between transmissions		$1/(2.2 * fSCL)$	—	s
203	Low period of SCL		$1/(2.2 * fSCL)$	—	s
204	High period of SCL		$1/(2.2 * fSCL)$	—	s
205	Start condition setup time		$1/(2.2 * fSCL)$	—	s
206	Start condition hold time		$1/(2.2 * fSCL)$	—	s
207	Data hold time		0	—	s
208	Data setup time		$1/(40 * fSCL)$	—	s
209	SDL/SCL rise time		—	$1/(10 * fSCL)$	s
210	SDL/SCL fall time		—	$1/(33 * fSCL)$	s
211	Stop condition setup time		$1/2(2.2 * fSCL)$	—	s

<sup>1</sup> SCL frequency is given by  $SCL = BrgClk\_frequency / ((BRG\ register + 3) * pre\_scaler * 2)$ .  
The ratio SyncClk/(Brg\_Clk/pre\_scaler) must be greater or equal to 4/1.

Figure 61 shows the I<sup>2</sup>C bus timing.

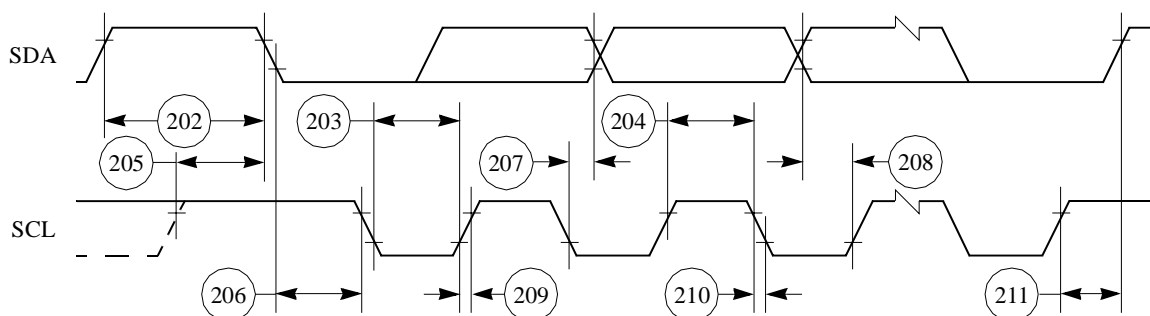

**Figure 61. I<sup>2</sup>C Bus Timing Diagram**

Figure 63 shows the JEDEC pinout of the PBGA package as viewed from the top surface.

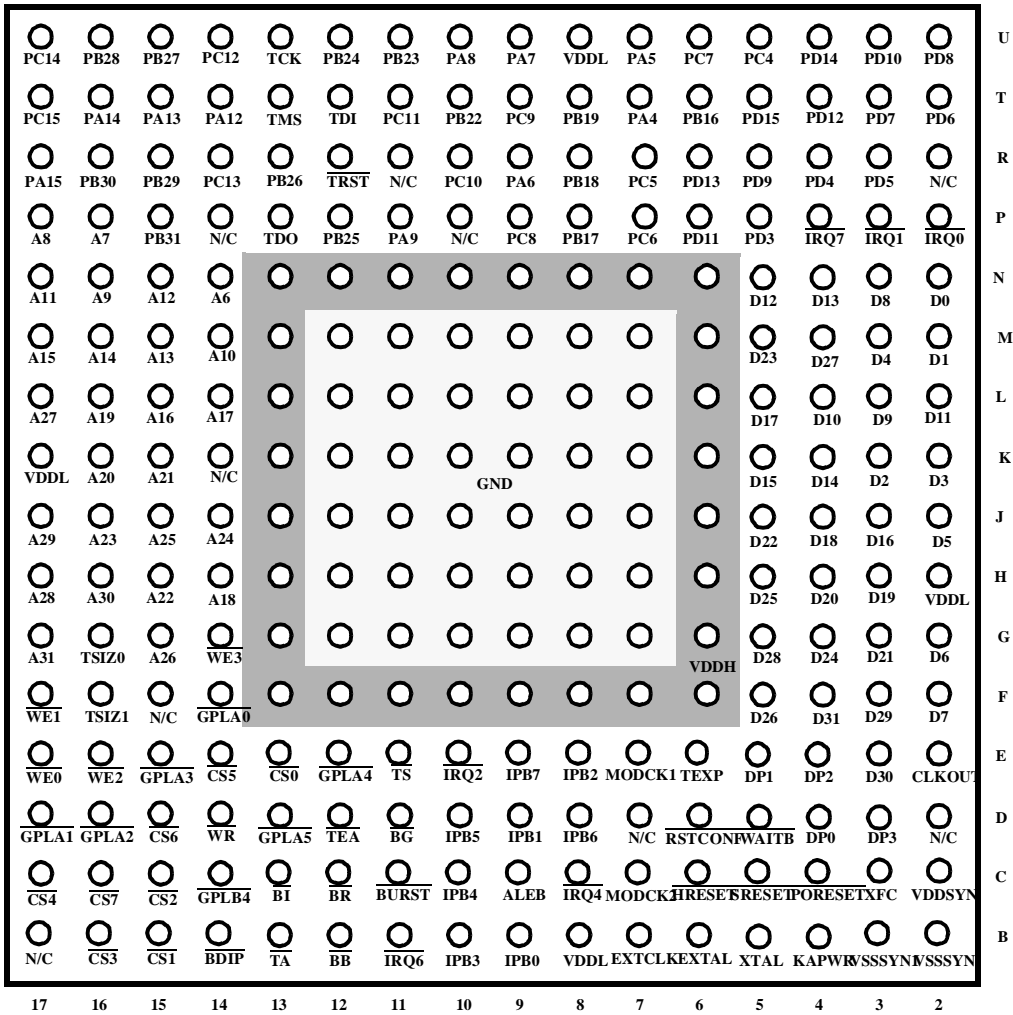


Figure 63. Pin Assignments for the PBGA (Top View)—JEDEC Standard

For more information on the printed circuit board layout of the PBGA package, including thermal via design and suggested pad layout, please refer to AN-1231/D, Plastic Ball Grid Array Application Note available from your local Freescale sales office.

Figure 64 shows the non-JEDEC package dimensions of the PBGA.

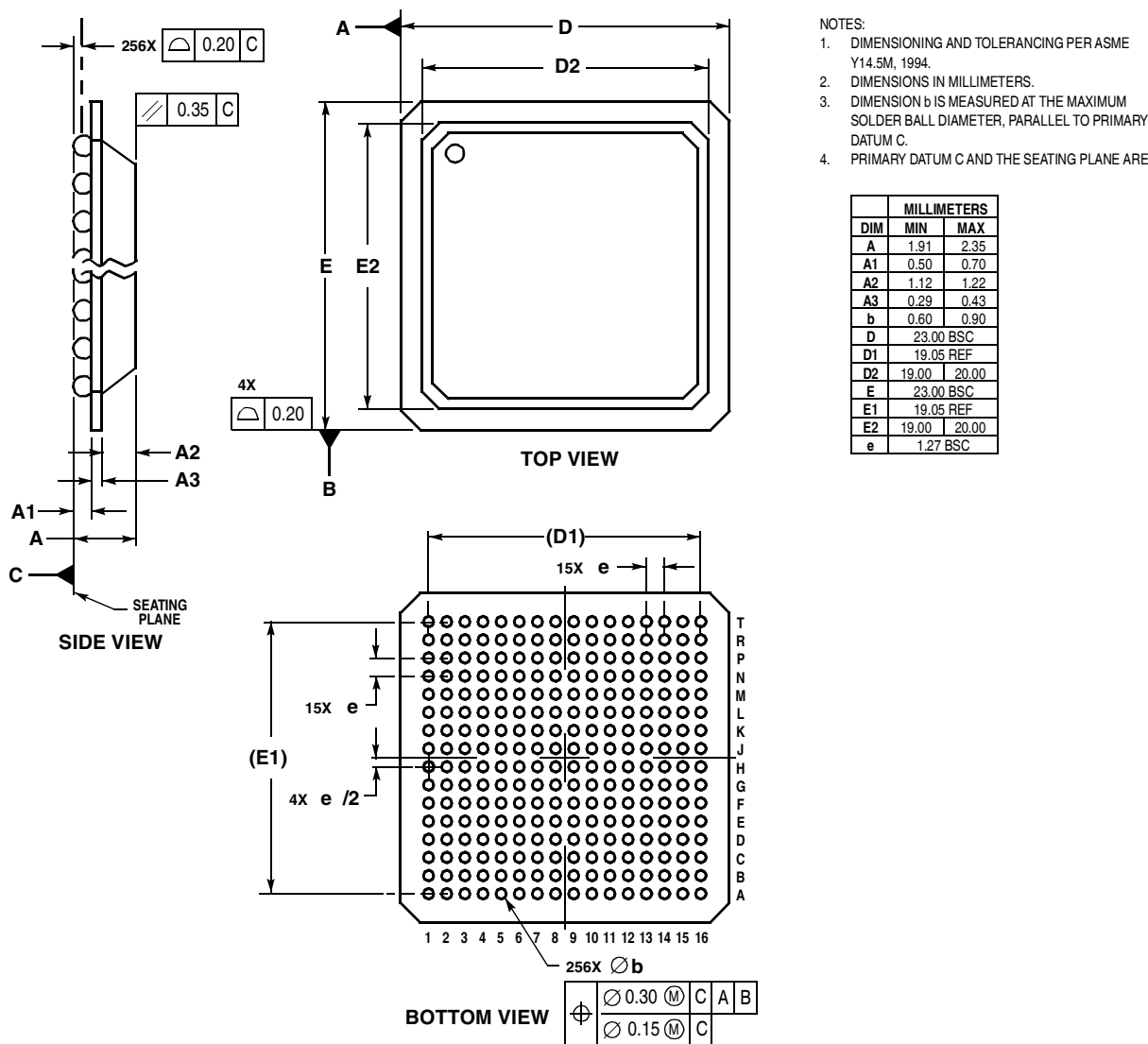


Figure 64. Package Dimensions for the Plastic Ball Grid Array (PBGA)—non-JEDEC Standard



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